
Device Type	V_{RRM} (1)	V_{DRM} (1)	V_{RSM} (1)
KK2700/18	1800	1800	2000
KK2700/20	2000	2000	2100

V_{RRM} = Repetitive peak reverse voltage
 V_{DRM} = Repetitive peak off state voltage
 V_{RSM} = Non repetitive peak reverse voltage (2)

Repetitive peak reverse leakage and off state leakage	I_{RRM}/I_{DRM}	5 mA 80 mA (3)
Critical rate of voltage rise	dv/dt (4)	

Peak gate power dissipation	P_{GM}		20		W	
Average gate power dissipation	$P_{G(AV)}$		4		W	
Gate-trigger current	I_{GT}		150		mA	$V_D=12V; R_L=30hms; T_j=+25^{\circ}C$
Gate- trigger voltage	V_{GT}	0.70	2.5		V	$V_D=12V; R_L=30hms; T_j=+25^{\circ}C$
Peak negative voltage	V_{GRM}		5		V	

Delay time	t_d		3.0	2.5	s	$I_{TM}=1000A; V_D=67\%V_{DRM}$ Gate pulse: $V_G=30V; R_G=10ohms;$ $t_r=0.1\ s; t_p=20\ s$
Turn-off time (with $V_R = -5\ V$)	t_q		40		s	$I_{TM} =2500\ A; di/dt =-25\ A/\ s;$ $V_R =50\ V; dv/dt=30V/\ s;$ $V_D= 67\%V_{DRM}; T_j=125^{\circ}C$
Reverse recovery charge	Q_{rr}				C	$I_{TM}=2500\ A; di/dt=-10A/\ s;$ $V_R=50\ V; T_j=125^{\circ}C$

Operating temperature	T_j	-40	+125		$^{\circ}C$
Storage temperature	T_{stg}	-40	+140		$^{\circ}C$
Thermal resistance - junction to case	$R_{\Theta(j-c)}$		0.01		$^{\circ}C/W$ Double sided cooled
Thermal resistance - case to heatsink	$R_{\Theta(c-s)}$		0.003		$^{\circ}C/W$ Double sided cooled
Mounting force	F	33	37	35	kN

